Search Notes



App	olica	tion	Con	trol	No.

Applicant(s)/Patent under Reexamination JOHNSON ET AL.

09/848,723 Examiner

Art Unit 2141

Djenane M. Bayard

	SEARCHED				
Class	Subclass	Date	Examiner		
709	224	2/13/2006	DB		
709	203	2/13/2006	DB		
709	218	2/13/2006	DB		
709	232	2/13/06	DB		
707	204	2/13/2006	DB		
707	205	2/13/2006	DB		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
709	224/232	2/13/2006	DB		
709	203/218	2/13/2006	DB		

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
East	2/13/2006	DB
IEEE, google scholar	2/13/2006	DB